Seminar on Climatic reliability of electronics: Global challenges and perspectives

20-21 March 2019

Technical University of Denmark









PROGRAMME Wednesday 20 March 2019

09:00-09:30	Registration and breakfast
09:30-10:30	Lecture on fundamentals of corrosion and relevance to electronic corrosion
10:30-11:00	Break
11:00-12:00	Lecture on humidity and intrinsic aspects of PCBAs causing climatic reliability issues in electronics
12:00-13:00	Lunch
13:00-14:00	Lecture on methods to improve humidity related relia- bility of PCBAs – Intrinsic and extrinsic methods
14:00-14:30	Theory to practice – some examples of how to im- prove reliability
14:30-15:00	Some basic tips for corrosion related failure analysis on PCBA
15:00-15:30	Break
15:30-17:00	Lab demonstration of some failure analysis methods
17:30-19:30	Reception

Workshop teachers:

Dr. Rajan Ambat, Professor, Centre for Electronic Corrosion, DTU Dr. Morten Jellesen, Senior Scientist, Centre for Electronic Corrosion, DTU

Thursday 21 March 2019

08:45-09:00	Breakfast
	Session 1
09:00-09:15	Introduction to the seminar and relevance of climatic reliability of electronics today Rajan Ambat, CELCORR, DTU, Denmark
09:15-09:45	Automotive electronics and ambient humidity Maxime Makarov, Renault Group, France
09:45-10:15	Environmental reliability testing demands of LEDs for automotive and outdoor applications Stefan Shoemaker, OSRAM, Germany
10:15-10:45	Break
	Session 2
10:45-11:15	PCBA cleanliness as a solution for humidity robustness Rajan Ambat, CELCORR, DTU
11:15-11:45	How wet is wet? Robust automotive electronics in humid environment Lothar Henneken, Bosch Automotive Electronics, Germany
11:45-12:15	New quality test for susceptibility of encapsulated elec- tronics to harmful gas corrosion Markus R. Meier, ZESTRON Europe
12:15-13:15	Lunch

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Session 3

13:15-13:45	Outgassing behaviour of SMT flux residue during reflow soldering Theresia Richter, Bosch Automotive Electronics, Germany
13:45-14:15	Humidity driven degradation in power semiconduc- tor devices Nando Kaminski, University of Bremen, Germany
14:15-14:45	Methodology for corrosion studies in microelectronic assemblies Kirsten Weide-Zaage, Uni. Hannovar, Germany & Hélène Fremont, Universite Bordeaux, France
14:45-15:15	Break
15:15-15:45	Unique solutions to prevent solder joint fatigue Gary Moffat, Retronix, UK
15:45-16:15	Corrosion of NiCr-conductors due to humidity Lutz Muller, Bosch Automotive Electronics, Germany
16:15-16:45	Effect of PCBA cleanliness on the performance of conformal coating Morten Jellesen, CELCORR, DTU, Denmark
16:45-17:00	Closing remarks Rajan Ambat, CELCORR, DTU, Denmark



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Feknologisk Videndeling ATV-SEMAPP.DK

SEMINAR VENUE Technical University of Denmark Anker Engelundsvej 1 2800 Lyngby Denmark

This seminar is organized by Centre for Electronic Corrosion (CELCORR), DTU and European Federation of Corrosion, Working Party 23 on "Corrosion Reliability of Electronics, EFC event No. 449

www.celcorr.com





